Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/802,056	CHOI ET AL.	
Examiner	Art Unit	
Dalena Tran	3664	

	SEAR	CHED	
Class	Subclass	Date	Examiner
701	221	speciale second	
	213	112/10/06	þ
	217		
73	1.38	16/19/0	101
342	357.08		
	357.14		
	457		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
see	cottonsed	11/6/07	DT	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	10/29/0	107